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H-987

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

A. NISHIMURA et al

Serial No. 09/869,274

Group Art Unit: 2823

Filed: June 26, 2001

Examiner: W. Coleman

For: SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE HAVING BUMP
ELECTRODES FOR SIGNAL OR POWER ONLY, AND TESTING PADS
THAT ARE NOT COUPLED TO BUMP ELECTRODES (As Amended)

REQUEST FOR FORM PTO-1449

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

April 2, 2004

Sir:

On June 26, 2001, the Applicants filed an Information Disclosure Statement (IDS) with copies of the cited references. However, the references AL (JP 4-26537), AM (JP 4-96343), and AO (JP 8-250498) on page 1 of the PTO-1449 and AM (JP 8-29451) on page 2 of the PTO-1449 have been crossed out. JP 8-29451 and JP 8-250498 were both discussed in the present specification. JP 4-26537 and JP 4-96343 were both listed in an International Search Report, which was provided to the U.S. Patent and Trademark Office. A copy of the date-stamped receipt is enclosed herewith.

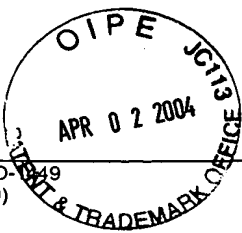
As indicated on the date-stamped receipt, copies of the documents have been submitted. Further, as set forth above, English-language statements of relevancy satisfying 37 C.F.R. § 1.98 have also been submitted. Therefore, the Applicants request the Examiner to initial and return the attached copy of the Forms PTO-1449 previously submitted, as an indication that these documents have been considered and that all requirements of 37 C.F.R. § 1.97-1.98 have been satisfied.

Respectfully submitted,



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Date: April 2, 2004



FORM PTO-149 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. H-987	SERIAL NO. 09/869,274
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT A. NISHIMURA et al	
		FILING DATE June 26, 2001	GROUP

U.S. PATENT DOCUMENTS

* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA 6,030,890	2/29/00	Iwabuchi			
	AB 6,008,543	12/28/99	Iwabuchi			
	AC 5,554,940	9/10/96	Hubacher			
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

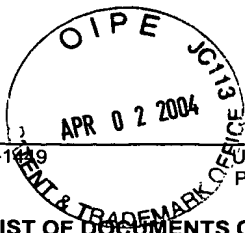
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	AL 4-26537	3/3/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM 4-96343	3/27/92	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AN 5-218042	8/27/93	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AO 8-250498	9/27/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AP 8-64633	3/8/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	IEEE/CPMT INTL ELECTRONICS MANUFACTURING TECHNOLOGY SYMPOSIUM, "Impact of Wafer Probe Damage on Flip Chip Yields and Reliability", M. Varnau et al, pp. 293-297.
	AS	
	AT	

EXAMINER

DATE CONSIDERED



FORM PTO-1029 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. H-987	SERIAL NO. 09/869,274
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT A. NISHIMURA et al	
		FILING DATE June 26, 2001	GROUP

U.S. PATENT DOCUMENTS

* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	8-340029	12/24/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AM	8-29451	2/2/96	Japan			<input type="checkbox"/>	<input type="checkbox"/>
	AN						<input type="checkbox"/>	<input type="checkbox"/>
	AO						<input type="checkbox"/>	<input type="checkbox"/>
	AP						<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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EXAMINER	DATE CONSIDERED
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Serial No.

Filed: June 26, 2001

For: SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE
AND MANUFACTURE THEREOF

Papers Filed Herewith:

1. Title Page; Description (120 pp.), 28 Claims, Abstract;
2. Declaration and Power of Attorney;
3. Check #3854 for \$1,804.00 (Filing Fee);
4. 38 sheets drawings (Figs. 1-59);
5. Preliminary Amendment;
6. Information Disclosure Statement, PTO-1449 Form, in duplicate; and Copies of documents cited;
7. copy of International Search Report;
8. List of Inventors' Names and Addresses;
9. PTO-1390 Transmittal; and
10. Serial No. postcard.



Receipt is hereby acknowledged of the papers filed, as identified in connection with the above-identified patent application.

COMMISSIONER OF PATENTS AND TRADEMARKS